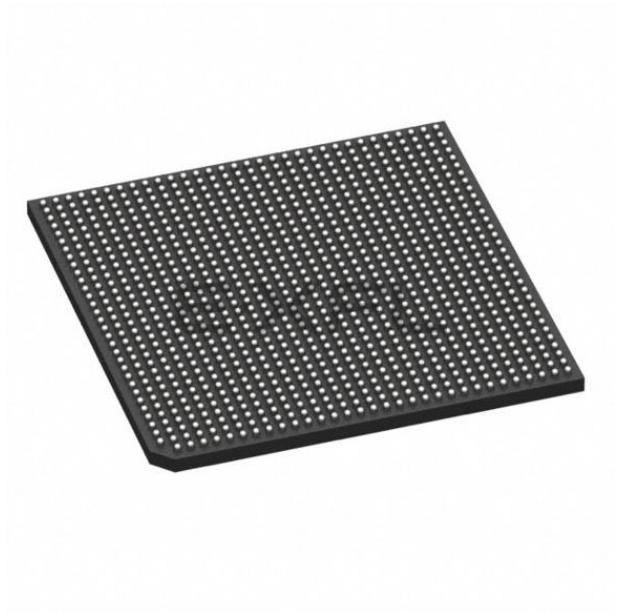

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.067GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572lpxarld

  - Ability to launch DMA from single write transaction
- Serial RapidIO interface unit
  - Supports *RapidIO Interconnect Specification, Revision 1.2*
  - Both 1x and 4x LP-serial link interfaces
  - Long- and short-haul electricals with selectable pre-compensation
  - Transmission rates of 1.25, 2.5, and 3.125 Gbaud (data rates of 1.0, 2.0, and 2.5 Gbps) per lane
  - Auto-detection of 1x- and 4x-mode operation during port initialization
  - Link initialization and synchronization
  - Large and small size transport information field support selectable at initialization time
  - 34-bit addressing
  - Up to 256 bytes data payload
  - All transaction flows and priorities
  - Atomic set/clr/inc/dec for read-modify-write operations
  - Generation of IO_READ_HOME and FLUSH with data for accessing cache-coherent data at a remote memory system
  - Receiver-controlled flow control
  - Error detection, recovery, and time-out for packets and control symbols as required by the RapidIO specification
  - Register and register bit extensions as described in part VIII (Error Management) of the RapidIO specification
  - Hardware recovery only
  - Register support is not required for software-mediated error recovery.
  - Accept-all mode of operation for fail-over support
  - Support for RapidIO error injection
  - Internal LP-serial and application interface-level loopback modes
  - Memory and PHY BIST for at-speed production test
- RapidIO–compliant message unit
  - 4 Kbytes of payload per message
  - Up to sixteen 256-byte segments per message
  - Two inbound data message structures within the inbox
  - Capable of receiving three letters at any mailbox
  - Two outbound data message structures within the outbox
  - Capable of sending three letters simultaneously
  - Single segment multicast to up to 32 devIDs
  - Chaining and direct modes in the outbox
  - Single inbound doorbell message structure
  - Facility to accept port-write messages

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings[1]

Characteristic		Symbol	Range	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 1.21	V	—
PLL supply voltage		AV_{DD}	–0.3 to 1.21	V	—
Core power supply for SerDes transceivers		SV_{DD}	–0.3 to 1.21	V	—
Pad power supply for SerDes transceivers		XV_{DD}	–0.3 to 1.21	V	—
DDR SDRAM Controller I/O supply voltage	DDR2 SDRAM Interface	GV_{DD}	–0.3 to 1.98	V	—
	DDR3 SDRAM Interface	—	–0.3 to 1.65		—
Three-speed Ethernet I/O, FEC management interface, MII management voltage		LV_{DD} (for eTSEC1 and eTSEC2) TV_{DD} (for eTSEC3 and eTSEC4, FEC)	–0.3 to 3.63 –0.3 to 2.75 –0.3 to 3.63 –0.3 to 2.75	V — —	2 2
DUART, system control and power management, I^2C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	—
Local bus and GPIO I/O voltage		BV_{DD}	–0.3 to 3.63 –0.3 to 2.75 –0.3 to 1.98	V	—
Input voltage	DDR2 and DDR3 SDRAM interface signals	MV_{IN}	–0.3 to (GV_{DD} + 0.3)	V	3
	DDR2 and DDR3 SDRAM interface reference	$MV_{REF}n$	–0.3 to (GV_{DD}/2 + 0.3)	V	—
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	–0.3 to (LV_{DD} + 0.3) –0.3 to (TV_{DD} + 0.3)	V	3
	Local bus and GPIO signals	BV_{IN}	–0.3 to (BV_{DD} + 0.3)	—	—
	DUART, SYSCLK, system control and power management, I^2C, and JTAG signals	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	3
Storage temperature range		T_{STG}	–55 to 150	°C	—

Notes:

1. Functional operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. The 3.63V maximum is only supported when the port is configured in GMII, MII, RMII or TBI modes; otherwise the 2.75V maximum applies. See Section 8.2, “FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications,” for details on the recommended operating conditions per protocol.
3. (M,L,O)V_{IN} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

2.1.3 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25 35	BV_{DD} = 3.3 V BV_{DD} = 2.5 V	1
	45(default) 45(default) 125	BV_{DD} = 3.3 V BV_{DD} = 2.5 V BV_{DD} = 1.8 V	
DDR2 signal	18 36 (half strength mode)	GV_{DD} = 1.8 V	2
DDR3 signal	20 40 (half strength mode)	GV_{DD} = 1.5 V	2
eTSEC/10/100 signals	45	L/TV_{DD} = 2.5/3.3 V	—
DUART, system control, JTAG	45	OV_{DD} = 3.3 V	—
I2C	150	OV_{DD} = 3.3 V	—

Notes:
1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSCR.
2. The drive strength of the DDR2 or DDR3 interface in half-strength mode is at T_j = 105°C and at GV_{DD} (min).

2.2 Power Sequencing

The MPC8572E requires its power rails to be applied in a specific sequence to ensure proper device operation. These requirements are as follows for power up:

1. V_{DD}, AV_{DD}_n, BV_{DD}, LV_{DD}, OV_{DD}, SV_{DD_SRDS1} and SV_{DD_SRDS2}, TV_{DD}, XV_{DD_SRDS1} and XV_{DD_SRDS2}
2. GV_{DD}

All supplies must be at their stable values within 50 ms.

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

To guarantee MCKE low during power-on reset, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-on reset, then the sequencing for GV_{DD} is not required.

Table 14 provides the current draw characteristics for $MV_{REF}n$.

Table 14. Current Draw Characteristics for MV_{REF} *n*

Parameter / Condition		Symbol	Min	Max	Unit	Note
Current draw for $MV_{REF}n$	DDR2 SDRAM	$I_{MVREF}n$	—	1500	µA	1
	DDR3 SDRAM			1250		

1. The voltage regulator for $MV_{REF}n$ must be able to supply up to 1500 µA or 1250 uA current for DDR2 or DDR3, respectively.

6.2 DDR2 and DDR3 SDRAM Interface AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR SDRAM controller interface. The DDR controller supports both DDR2 and DDR3 memories. Note that although the minimum data rate for most off-the-shelf DDR3 DIMMs available is 800 MHz, JEDEC specification does allow the DDR3 to run at the data rate as low as 606 MHz. Unless otherwise specified, the AC timing specifications described in this section for DDR3 is applicable for data rate between 606 MHz and 800 MHz, as long as the DC and AC specifications of the DDR3 memory to be used are compliant to both JEDEC specifications as well as the specifications and requirements described in this MPC8572E hardware specifications document.

6.2.1 DDR2 and DDR3 SDRAM Interface Input AC Timing Specifications

Table 15, Table 16, and Table 17 provide the input AC timing specifications for the DDR controller when interfacing to DDR2 and DDR3 SDRAM.

Table 15. DDR2 SDRAM Interface Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with GV_{DD} of 1.8 V ± 5%

Parameter		Symbol	Min	Max	Unit	Notes
AC input low voltage	>=667 MHz	V_{ILAC}	—	$MV_{REF}n$ – 0.20	V	—
	<= 533 MHz		—	$MV_{REF}n$ – 0.25		
AC input high voltage	>=667 MHz	V_{IHAC}	$MV_{REF}n$ + 0.20	—	V	—
—	<= 533 MHz		$MV_{REF}n$ + 0.25	—		

Table 16. DDR3 SDRAM Interface Input AC Timing Specifications for 1.5-V Interface

At recommended operating conditions with GV_{DD} of 1.5 V ± 5%. DDR3 data rate is between 606 MHz and 800 MHz.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{ILAC}	—	$MV_{REF}n$ – 0.175	V	—
AC input high voltage	V_{IHAC}	$MV_{REF}n$ + 0.175	—	V	—

7.2 DUART AC Electrical Specifications

Table 22 provides the AC timing parameters for the DUART interface.

Table 22. DUART AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter	Value	Unit	Notes
Minimum baud rate	f_{CCB}/1,048,576	baud	1, 2
Maximum baud rate	f_{CCB}/16	baud	1, 2, 3
Oversample rate	16	—	1, 4

Notes:
1. Guaranteed by design
2. f_{CCB} refers to the internal platform clock frequency.
3. Actual attainable baud rate is limited by the latency of interrupt processing.
4. The middle of a start bit is detected as the 8^{th} sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16^{th} sample.

8 Ethernet: Enhanced Three-Speed Ethernet (eTSEC)

This section provides the AC and DC electrical characteristics for the enhanced three-speed Ethernet controller.

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—FIFO/GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics

The electrical characteristics specified here apply to all FIFO mode, gigabit media independent interface (GMII), media independent interface (MII), ten-bit interface (TBI), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), and reduced media independent interface (RMII) signals except management data input/output (MDIO) and management data clock (MDC), and serial gigabit media independent interface (SGMII). The RGMII, RTBI and FIFO mode interfaces are defined for 2.5 V, while the GMII, MII, RMII, and TBI interfaces can operate at both 2.5 V and 3.3V .

The GMII, MII, or TBI interface timing is compliant with IEEE 802.3. The RGMII and RTBI interfaces follow the Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3 (12/10/2000). The RMII interface follows the RMII Consortium RMII Specification Version 1.2 (3/20/1998).

The electrical characteristics for MDIO and MDC are specified in Section 9, “Ethernet Management Interface Electrical Characteristics.”

The electrical characteristics for SGMII is specified in Section 8.3, “SGMII Interface Electrical Characteristics.” The SGMII interface conforms (with exceptions) to the Serial-GMII Specification Version 1.8.

Figure 11 shows the GMII receive AC timing diagram.

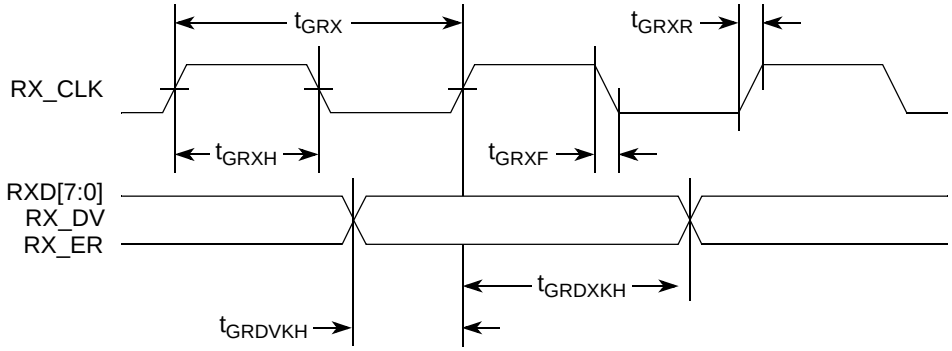

Figure 11. GMII Receive AC Timing Diagram

8.2.3 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.3.1 MII Transmit AC Timing Specifications

Table 29 provides the MII transmit AC timing specifications.

Table 29. MII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX}[2]	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDX}	1	5	15	ns
TX_CLK data clock rise (20%-80%)	t_{MTXR}[2]	1.0	—	4.0	ns
TX_CLK data clock fall (80%-20%)	t_{MTXF}[2]	1.0	—	4.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Table 35. RMII Transmit AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TSECn_TX_CLK to RMII data TXD[1:0], TX_EN delay	t_{RMTDX}	1.0	—	10.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 19 shows the RMII transmit AC timing diagram.

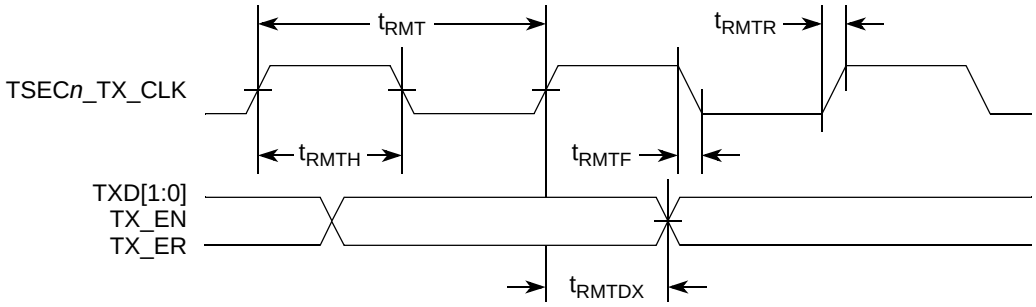

Figure 19. RMII Transmit AC Timing Diagram

8.2.7.2 RMII Receive AC Timing Specifications

Table 36 shows the RMII receive AC timing specifications.

Table 36. RMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TSECn_TX_CLK clock period	t_{RMR}	15.0	20.0	25.0	ns
TSECn_TX_CLK duty cycle	t_{RMRH}	35	50	65	%
TSECn_TX_CLK peak-to-peak jitter	t_{RMRJ}	—	—	250	ps
Rise time TSECn_TX_CLK (20%–80%)	t_{RMRR}	1.0	—	2.0	ns
Fall time TSECn_TX_CLK (80%–20%)	t_{RMRF}	1.0	—	2.0	ns
RXD[1:0], CRS_DV, RX_ER setup time to TSECn_TX_CLK rising edge	t_{RMRDV}	4.0	—	—	ns

Table 38. SGMII DC Transmitter Electrical Characteristics (continued)

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Change in V_{OS} between "0" and "1"	ΔV_{OS}	—	—	25	mV	—
Output current on short to GND	I_{SA}, I_{SB}	—	—	40	mA	—

Note:

1. This will not align to DC-coupled SGMII. $XV_{DD\_SRDS2\text{-}Typ}$=1.1 V.
2. $|V_{OD}| = |V_{SD2\_TXn} - V_{\overline{SD2\_TXn}}|$. $|V_{OD}|$ is also referred as output differential peak voltage. $V_{TX\text{-}DIFFp\text{-}p} = 2*|V_{OD}|$.
3. The $|V_{OD}|$ value shown in the table assumes the following transmit equalization setting in the XMITEQ**AB** (for SerDes 2 lanes A & B) or XMITEQ**EF** (for SerDes 2 lanes E & E) bit field of MPC8572E's SerDes 2 Control Register:
   - •The MSbit (bit 0) of the above bit field is set to zero (selecting the full $V_{DD\text{-}DIFF\text{-}p\text{-}p}$ amplitude - power up default);
   - •The LSbits (bit [1:3]) of the above bit field is set based on the equalization setting shown in table.
4. V_{OS} is also referred to as output common mode voltage.
   - 5.The $|V_{OD}|$ value shown in the Typ column is based on the condition of $XV_{DD\_SRDS2\text{-}Typ}$=1.1V, no common mode offset variation (V_{OS} =550mV), SerDes2 transmitter is terminated with 100-Ω differential load between SD2_TX[n] and $\overline{SD2\_TX}$[n].

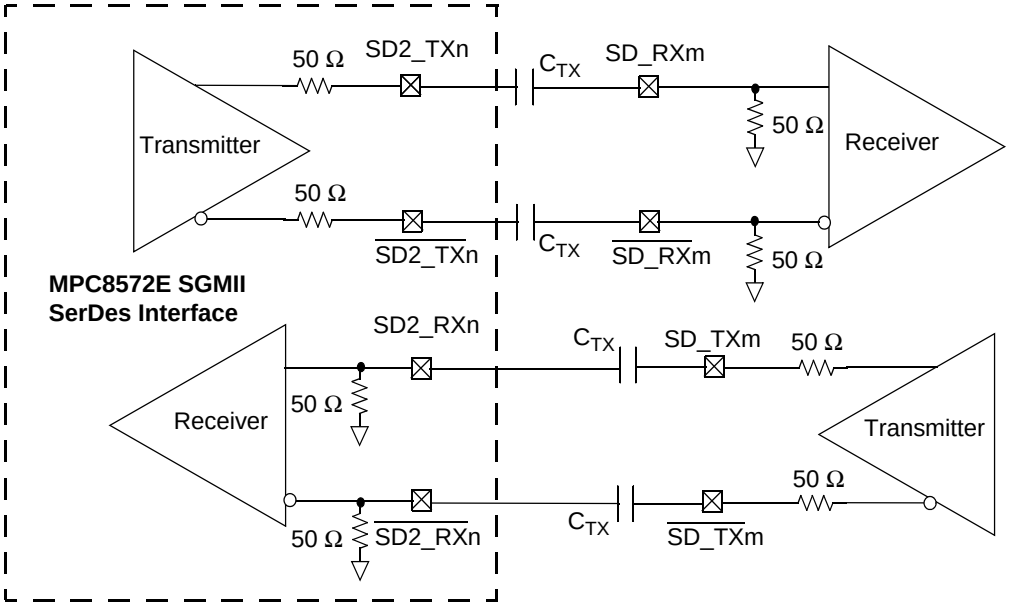

Figure 22. 4-Wire AC-Coupled SGMII Serial Link Connection Example

Table 48 provides the DC electrical characteristics for the local bus interface operating at BV_{DD} = 1.8 V DC.

Table 48. Local Bus DC Electrical Characteristics (1.8 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 1.8V	BV_{DD}	1.71	1.89	V
High-level input voltage	V_{IH}	0.65 x BV_{DD}	BV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.35 x BV_{DD}	V
Input current (BV_{IN} [1] = 0 V or BV_{IN} = BV_{DD})	I_{IN}	TBD	TBD	µA
High-level output voltage (I_{OH} = –100 µA)	V_{OH}	BV_{DD} – 0.2	—	V
High-level output voltage (I_{OH} = –2 mA)	V_{OH}	BV_{DD} – 0.45	—	V
Low-level output voltage (I_{OL} = 100 µA)	V_{OL}	—	0.2	V
Low-level output voltage (I_{OL} = 2 mA)	V_{OL}	—	0.45	V

Note:
1. The symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in Table 1.

10.2 Local Bus AC Electrical Specifications

Table 49 describes the general timing parameters of the local bus interface at BV_{DD} = 3.3 V DC.

Table 49. Local Bus General Timing Parameters (BV_{DD} = 3.3 V DC)—PLL Enabled

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%.

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	6.67	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7,8
Input setup to local bus clock (except $\overline{\text{LGTA}}$/LUPWAIT)	$t_{LBIVKH1}$	1.8	—	ns	3, 4
$\overline{\text{LGTA}}$/LUPWAIT input setup to local bus clock	$t_{LBIVKH2}$	1.7	—	ns	3, 4
Input hold from local bus clock (except $\overline{\text{LGTA}}$/LUPWAIT)	$t_{LBIXKH1}$	1.0	—	ns	3, 4
$\overline{\text{LGTA}}$/LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.0	—	ns	3, 4
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.3	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.4	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.3	ns	3

Table 51. Local Bus General Timing Parameters (BV_{DD} = 1.8 V DC)—PLL Enabled (continued)

At recommended operating conditions with BV_{DD} of 1.8 V ± 5% (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{LGTA}}$/LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.2	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	3.2	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	3.2	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	3.2	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	3.2	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.9	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.9	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 1.8-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 29 provides the AC test load for the local bus.

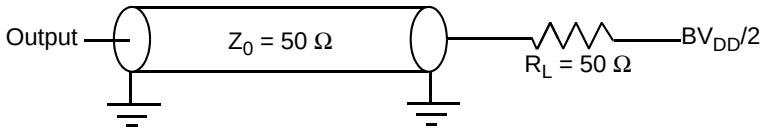

Figure 29. Local Bus AC Test Load

11 Programmable Interrupt Controller

In IRQ edge trigger mode, when an external interrupt signal is asserted (according to the programmed polarity), it must remain asserted for at least 3 system clocks (SYSCLK periods).

12 JTAG

This section describes the AC electrical specifications for the IEEE 1149.1 (JTAG) interface of the MPC8572E.

Table 53 provides the JTAG AC timing specifications as defined in Figure 37 through Figure 39.

Table 53. JTAG AC Timing Specifications (Independent of SYSCLK) [1]

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%.

Parameter	Symbol [2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	15	—	ns	—
JTAG external clock rise and fall times	t_{JTGR} & t_{JTGF}	0	2	ns	6
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	3
Input setup times: Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 0	 — —	ns	4
Input hold times: Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 20 25	 — —	ns	4
Valid times: Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 4 4	 20 25	ns	5
Output hold times: Boundary-scan data TDO	 t_{JTKLDX} t_{JTKLOX}	 30 30	 — —	ns	5

Table 54. I²C DC Electrical Characteristics (continued)

Capacitance for each I/O pin	C_I	—	10	pF	—

Notes:
1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. Refer to the *MPC8572E PowerQUICC™ III Integrated Host Processor Family Reference Manual* for information on the digital filter used.
3. I/O pins will obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

Table 55 provides the AC timing parameters for the I²C interfaces.

Table 55. I²C AC Electrical Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol[1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz[4]
Low period of the SCL clock	t_{I2CL}	1.3	—	µs
High period of the SCL clock	t_{I2CH}	0.6	—	µs
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	µs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	µs
Data setup time	t_{I2DVKH}	100	—	ns
Data input hold time: CBUS compatible masters I²C bus devices	t_{I2DXKL}	 — 0[2]	 — —	µs
Data output delay time	t_{I2OVKL}	—	0.9[3]	µs
Setup time for STOP condition	t_{I2PVKH}	0.6	—	µs
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	µs
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V

15 High-Speed Serial Interfaces (HSSI)

The MPC8572E features two Serializer/Deserializer (SerDes) interfaces to be used for high-speed serial interconnect applications. The SerDes1 interface can be used for PCI Express and/or Serial RapidIO data transfers. The SerDes2 is dedicated for SGMII application.

This section describes the common portion of SerDes DC electrical specifications, which is the DC requirement for SerDes Reference Clocks. The SerDes data lane's transmitter and receiver reference circuits are also shown.

15.1 Signal Terms Definition

The SerDes utilizes differential signaling to transfer data across the serial link. This section defines terms used in the description and specification of differential signals.

Figure 43 shows how the signals are defined. For illustration purpose, only one SerDes lane is used for description. The figure shows waveform for either a transmitter output (SDn_TX and $\overline{\text{SDn\_TX}}$) or a receiver input (SDn_RX and $\overline{\text{SDn\_RX}}$). Each signal swings between A Volts and B Volts where A > B.

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. **Single-Ended Swing**

   The transmitter output signals and the receiver input signals SDn_TX, $\overline{\text{SDn\_TX}}$, SDn_RX and $\overline{\text{SDn\_RX}}$ each have a peak-to-peak swing of A - B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. **Differential Output Voltage, V_{OD}** (or **Differential Output Swing**):

   The Differential Output Voltage (or Swing) of the transmitter, V_{OD}, is defined as the difference of the two complimentary output voltages: $V_{SDn\_TX} - V_{\overline{SDn\_TX}}$. The V_{OD} value can be either positive or negative.

3. **Differential Input Voltage, V_{ID}** (or **Differential Input Swing**):

   The Differential Input Voltage (or Swing) of the receiver, V_{ID}, is defined as the difference of the two complimentary input voltages: $V_{SDn\_RX} - V_{\overline{SDn\_RX}}$. The V_{ID} value can be either positive or negative.

4. **Differential Peak Voltage, V_{DIFFp}**

   The peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak Voltage, $V_{DIFFp} = |A - B|$ Volts.

5. **Differential Peak-to-Peak, $V_{DIFFp-p}$**

   Because the differential output signal of the transmitter and the differential input signal of the receiver each range from A – B to –(A – B) Volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak-to-Peak Voltage, $V_{DIFFp-p} = 2*V_{DIFFp} = 2 * |(A - B)|$ Volts, which is twice of differential swing in amplitude, or twice of the differential peak. For example, the output differential peak-peak voltage can also be calculated as $V_{TX-DIFFp-p} = 2*|V_{OD}|$.

SD1_REF_CLK for PCI Express and Serial RapidIO, or SD2_REF_CLK and SD2_REF_CLK for the SGMII interface respectively.

The following sections describe the SerDes reference clock requirements and some application information.

15.2.1 SerDes Reference Clock Receiver Characteristics

Figure 44 shows a receiver reference diagram of the SerDes reference clocks. Characteristics are as follows:

- The supply voltage requirements for XV_{DD_SRDS2} are specified in Table 1 and Table 2.
- SerDes Reference Clock Receiver Reference Circuit Structure
  - The SD*n*_REF_CLK and SD*n*_REF_CLK are internally AC-coupled differential inputs as shown in Figure 44. Each differential clock input (SD*n*_REF_CLK or SD*n*_REF_CLK) has on-chip 50-Ω termination to SGND_SRDSn (xcorevss) followed by on-chip AC-coupling.
  - The external reference clock driver must be able to drive this termination.
  - The SerDes reference clock input can be either differential or single-ended. Refer to the Differential Mode and Single-ended Mode description below for further detailed requirements.
- The maximum average current requirement that also determines the common mode voltage range
  - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (refer to the following bullet for more detail), because the input is AC-coupled on-chip.
  - This current limitation sets the maximum common mode input voltage to be less than 0.4 V (0.4 V/50 = 8 mA) while the minimum common mode input level is 0.1 V above SGND_SRDS*n* (xcorevss). For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0-0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
  - If the device driving the SD*n*_REF_CLK and SD*n*_REF_CLK inputs cannot drive 50 Ω to SGND_SRDS*n* (xcorevss) DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.
- The input amplitude requirement
  - This requirement is described in detail in the following sections.

16.5.1 Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in Figure 57.

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D– not being exactly matched in length at the package pin boundary.

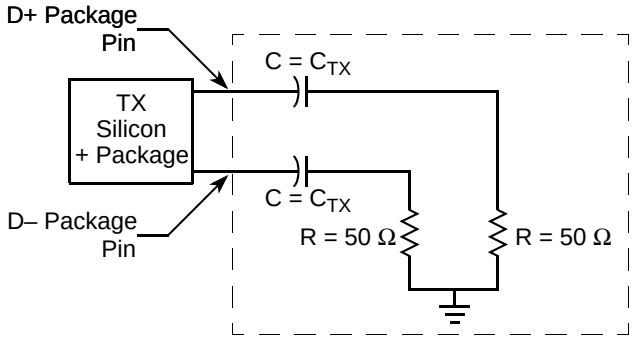

Figure 57. Compliance Test/Measurement Load

17 Serial RapidIO

This section describes the DC and AC electrical specifications for the RapidIO interface of the MPC8572E for the LP-Serial physical layer. The electrical specifications cover both single and multiple-lane links. Two transmitters (short run and long run) and a single receiver are specified for each of three baud rates, 1.25, 2.50, and 3.125 GBaud.

Two transmitter specifications allow for solutions ranging from simple board-to-board interconnect to driving two connectors across a backplane. A single receiver specification is given that accepts signals from both the short run and long run transmitter specifications.

The short run transmitter should be used mainly for chip-to-chip connections on either the same printed circuit board or across a single connector. This covers the case where connections are made to a mezzanine (daughter) card. The minimum swings of the short run specification reduce the overall power used by the transceivers.

The long run transmitter specifications use larger voltage swings that are capable of driving signals across backplanes. This allows a user to drive signals across two connectors and a backplane. The specifications allow a distance of at least 50 cm at all baud rates.

All unit intervals are specified with a tolerance of +/– 100 ppm. The worst case frequency difference between any transmit and receive clock is 200 ppm.

To ensure interoperability between drivers and receivers of different vendors and technologies, AC coupling at the receiver input must be used.

link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12}. The eye pattern shall be measured with AC coupling and the compliance template centered at 0 Volts differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter Test Pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 Volts differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

17.8.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in Section 17.6, “Receiver Specifications,” and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 60 and Table 75. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 17.6, “Receiver Specifications,” is then added to the signal and the test load is replaced by the receiver being tested.

18 Package Description

This section describes package parameters, pin assignments, and dimensions.

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
LGPL0/LFCLE	UPM General Purpose Line 0 / Flash Command Latch Enable	J13	O	BV_{DD}	5, 9
LGPL1/$\overline{\text{LFALE}}$	UPM General Purpose Line 1/ Flash Address Latch Enable	J16	O	BV_{DD}	5, 9
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$	UPM General Purpose Line 2 / Output Enable / Flash Read Enable	A27	O	BV_{DD}	5, 8, 9
LGPL3/$\overline{\text{LFWP}}$	UPM General Purpose Line 3 / Flash Write Protect	K16	O	BV_{DD}	5, 9
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/LPBSE/LFRB	UPM General Purpose Line 4 / Target Ack / Wait / Parity Byte Select / Flash Ready-Busy	L17	I/O	BV_{DD}	—
LGPL5	UPM General Purpose Line 5 / Amux	B26	O	BV_{DD}	5, 9
LCLK[0:2]	Local Bus Clock	F17, F16, A23	O	BV_{DD}	—
LSYNC_IN	Local Bus DLL Synchronization	B22	I	BV_{DD}	—
LSYNC_OUT	Local Bus DLL Synchronization	A21	O	BV_{DD}	—
DMA					
$\overline{\text{DMA1\_DACK}}$[0:1]	DMA Acknowledge	W25, U30	O	OV_{DD}	21
$\overline{\text{DMA2\_DACK}}$[0]	DMA Acknowledge	AA26	O	OV_{DD}	5, 9
$\overline{\text{DMA1\_DREQ}}$[0:1]	DMA Request	Y29, V27	I	OV_{DD}	—
$\overline{\text{DMA2\_DREQ}}$[0]	DMA Request	V29	I	OV_{DD}	—
$\overline{\text{DMA1\_DDONE}}$[0:1]	DMA Done	Y28, V30	O	OV_{DD}	5, 9
$\overline{\text{DMA2\_DDONE}}$[0]	DMA Done	AA28	O	OV_{DD}	5, 9
$\overline{\text{DMA2\_DREQ}}$[2]	DMA Request	M23	I	BV_{DD}	—
Programmable Interrupt Controller					
$\overline{\text{UDE0}}$	Unconditional Debug Event Processor 0	AC25	I	OV_{DD}	—
$\overline{\text{UDE1}}$	Unconditional Debug Event Processor 1	AA25	I	OV_{DD}	—
$\overline{\text{MCP0}}$	Machine Check Processor 0	M28	I	OV_{DD}	—
$\overline{\text{MCP1}}$	Machine Check Processor 1	L28	I	OV_{DD}	—
IRQ[0:11]	External Interrupts	T24, R24, R25, R27, R28, AB27, AB28, P27, R30, AC28, R29, T31	I	OV_{DD}	—

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD1_RX[7:0]	Receive Data (positive)	P32, N30, M32, L30, G30, F32, E30, D32	I	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_RX}}$[7:0]	Receive Data (negative)	P31, N29, M31, L29, G29, F31, E29, D31	I	XV_{DD_SRDS1}	—
SD1_TX[7]	PCIe1 Tx Data Lane 7 / SRIO or PCIe2 Tx Data Lane 3 / PCIe3 TX Data Lane 1	M26	O	XV_{DD_SRDS1}	—
SD1_TX[6]	PCIe1 Tx Data Lane 6 / SRIO or PCIe2 Tx Data Lane 2 / PCIe3 TX Data Lane 0	L24	O	XV_{DD_SRDS1}	—
SD1_TX[5]	PCIe1 Tx Data Lane 5 / SRIO or PCIe2 Tx Data Lane 1	K26	O	XV_{DD_SRDS1}	—
SD1_TX[4]	PCIe1 Tx Data Lane 4 / SRIO or PCIe2 Tx Data Lane 0	J24	O	XV_{DD_SRDS1}	—
SD1_TX[3]	PCIe1 Tx Data Lane 3	G24	O	XV_{DD_SRDS1}	—
SD1_TX[2]	PCIe1 Tx Data Lane 2	F26	O	XV_{DD_SRDS1}	—
SD1_TX[1]	PCIe1 Tx Data Lane 1]	E24	O	XV_{DD_SRDS1}	—
SD1_TX[0]	PCIe1 Tx Data Lane 0	D26	O	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_TX}}$[7:0]	Transmit Data (negative)	M27, L25, K27, J25, G25, F27, E25, D27	O	XV_{DD_SRDS1}	—
SD1_PLL_TPD	PLL Test Point Digital	J32	O	XV_{DD_SRDS1}	17
SD1_REF_CLK	PLL Reference Clock	H32	I	XV_{DD_SRDS1}	—
$\overline{\text{SD1\_REF\_CLK}}$	PLL Reference Clock Complement	H31	I	XV_{DD_SRDS1}	—
Reserved	—	C29, K32	—	—	26
Reserved	—	C30, K31	—	—	27
Reserved	—	C24, C25, H26, H27	—	—	28
Reserved	—	AL20, AL21	—	—	29
SerDes (x4) SGMII					
SD2_RX[3:0]	Receive Data (positive)	AK32, AJ30, AF30, AE32	I	XV_{DD_SRDS2}	—

Table 82. DDR Clock Ratio (continued)

Binary Value of TSEC_1588_CLK_OUT, TSEC_1588_PULSE_OUT1, TSEC_1588_PULSE_OUT2 Signals	DDR:DDRCLK Ratio
101	12:1
110	14:1
111	Synchronous mode

19.5 Frequency Options

19.5.1 Platform to Sysclk Frequency Options

Table 83 shows the expected frequency values for the platform frequency when using the specified CCB clock to SYSCLK ratio.

Table 83. Frequency Options for Platform Frequency

CCB to SYSCLK Ratio	SYSCLK (MHz)							
	33.33	41.66	50	66.66	83	100	111	133.33
	Platform /CCB Frequency (MHz)							
4						400	444	533
5					415	500	555	
6				400	498	600		
8			400	533				
10		417	500					
12	400	500	600					

19.5.2 Minimum Platform Frequency Requirements for High-Speed Interfaces

Section 4.4.3.6, “I/O Port Selection,” in the *MPC8572E PowerQUICC III Integrated Host Processor Family Reference Manual* describes various high-speed interface configuration options. Note that the CCB clock frequency must be considered for proper operation of such interfaces as described below.

For proper PCI Express operation, the CCB clock frequency must be greater than or equal to:

$$\frac{527\ \text{MHz} \times (\text{PCI Express link width})}{8}$$

See Section 21.1.3.2, “Link Width,” in the *MPC8572E PowerQUICC III Integrated Host Processor Family Reference Manual* for PCI Express interface width details. Note that the “PCI Express link width”

21 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8572E.

21.1 System Clocking

The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 19.2, "CCB/SYSCLK PLL Ratio." The MPC8572E includes seven PLLs, with the following functions:

- Two core PLLs have ratios that are individually configurable. Each e500 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in Section 19.3, "e500 Core PLL Ratio."
- The DDR complex PLL generates the clocking for the DDR controllers.
- The local bus PLL generates the clock for the local bus.
- The PLL for the SerDes1 module is used for PCI Express and Serial Rapid IO interfaces.
- The PLL for the SerDes2 module is used for the SGMII interface.

21.2 Power Supply Design

21.2.1 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD}_PLAT, AV_{DD}_CORE0, AV_{DD}_CORE1, AV_{DD}_DDR, AV_{DD}_LBIU, AV_{DD}_SRDS1 and AV_{DD}_SRDS2 respectively). The AV_{DD} level should always be equivalent to V_{DD}, and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 62, one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of the 1023 FC-PBGA footprint, without the inductance of vias.